


INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Docket: 1011-59137		App: 10/039,934	
				Applicant: Mohammed Ali AbdEl-Halim AbdEl-Wahid			
				Filed: October 26, 2001		Art Unit: 2133	
PATENT DOCUMENTS							
Init.*		Number	Date	Name	Class	Sub	Filed
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OTHER DOCUMENTS							
WJ			Fluence Technology Inc., "BISTMaxx™ Product Catalog," 38 p. (September 2000)				
WJ			Texas Instruments, "IEEE Std 1149.1 (JTAG) Testability Primer," 146 p. (1997)				
WJ			LogicVision, "LogicVision - PLL BIST," 1 p. (downloaded from http://www.logicvision.com/products/pll.html on April 10, 2001)				
WJ			Chatterjee and Nagi, "Design for Testability and Built-In Self-Test of Mixed-Signal Circuits: A Tutorial," <i>IEEE 10th Int'l Conference on VLSI Design</i> , pp. 388-92				
WJ			Wey, "Mixed-Signal Circuit Testing -- A Review," <i>Third Int'l Conference on Electronics, Circuits and Systems</i> , pp. 1064-67 (1996)				
WJ			Lin et al., "Automatic BIST Design Tool for Mixed-Signal Circuits," <i>AUTOTESTCON '98: IEEE Systems Readiness Technology Conference</i> , 97-102 (1998)				
WJ			Lubaszewski et al., "Design of Self-Checking Fully Differential Circuits and Boards," <i>IEEE Transactions on VLSI Systems</i> , vol. 8, no. 2, pp. 113-28 (April 2000)				

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			<p align="center">  </p>			
MS						"IEEE Standard for a Mixed-Signal Test Bus," <i>IEEE Std. 1149.4</i> , 84 pp. (2000)
MS						"IEEE Standard Test Access Port and Boundary-Scan Architecture," <i>IEEE Std. 1149.1-1a</i> , 172 pp. (1993)
MS						Nicolaidis & Zorian, "Scaling Deeper to Submicron: On-Line Testing to the Rescue," <i>IEEE Proceedings of the Design, Automation and Test in Europe Conference and Exhibition</i> , 1 p. (1999)
MS			Milor, "A Tutorial Introduction to Research on Analog and Mixed-Signal Circuit Testing," <i>IEEE Transactions on Circuits and Systems--II: Analog and Digital Signal Processing</i> , vol. 45, no. 10, pp. 1389-1407 (October 1998)			
EXAMINER: <i>John Smith</i>			DATE <i>5/25/04</i>			
<p>*Examiner: Initial if considered, whether or not in conformance with MPEP 609; draw line through cite if not in conformance and not considered. Send copy.</p>						

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